

B1-1: Advanced Techniques (TEM/STEM)

- B11-O-01 Atomic-Scale STEM Characterization of Grain Boundaries in Oxides
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- B11-O-02 Mapping Valance and Coordination by Monochromated STEM EELS
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- B11-O-03 Quantification of Oxygen Vacancies in Nanostructured Oxides by TEM Techniques: Electron Energy Loss Spectroscopy and Negative Cs Imaging
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- B11-O-05 Role of Defect as a Diffusion Barrier for Carriers in InGaN/GaN Quantum Wells
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- B11-O-07 Electron Tomography Observation of Dislocation Morphology near Surfaces of Mo (001) Thin Foils
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- B11-O-08 Rapid 3D Reconstruction in the EDS Tomography by Using Iterative Series Reduction (ISER) Method
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- B11-O-10 In situ Atomic Scale Mechanical Microscopy
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B11-O-12	Development of Hollow Cone Dark Field Environmental Electron Microscopy and Their Biological Application <i>Tsu-Hao Yang, Yu-Hung Weng, Hung-Tien Zheng, Shih-Yi Liu, Chun-Ying Tsai, Fan-Gang Tseng and Fu-Ron Chen</i> . Department of Engineering and System Science, National Tsing Hua Universityi16
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B11-O-15	Simultaneous Realization of Foucault Imaging and Small Angle Electron Diffraction by Conventional TEM <i>Hiroshi Nakajima¹, Atsuhiko Kotani¹, Yui Ishii¹, Ken Harada^{1,2} and Shigeo Mori¹</i> . ¹ Department of Materials Science, Osaka Prefecture University, ² Research and Development Group, Hitachi Ltd.i17
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